

FDP10N50U / FDPF10N50UT N-Channel MOSFET 500V, 8A, 1.05Ω

Features

- R_{DS(on)} = 0.85Ω (Typ.) @ V_{GS} = 10V, I_D = 4A
- Low Gate Charge (Typ. 18nC)
- Low C_{rss} (Typ. 9pF)
- · Fast Switching
- 100% Avalanche Tested
- Improved dv/dt Capability
- RoHS Compliant



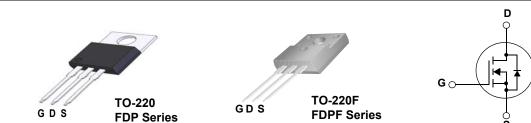
November 2009



Description

These N-Channel enhancement mode power field effect transistors are p roduced using Fa irchild's proprietary, planar stripe, DMOS technology.

This advance technology has been especially tailored to minimize on-state r esistance, prov ide sup erior switching per formance, and wit hstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switching mode power supplies and active power factor correction.



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

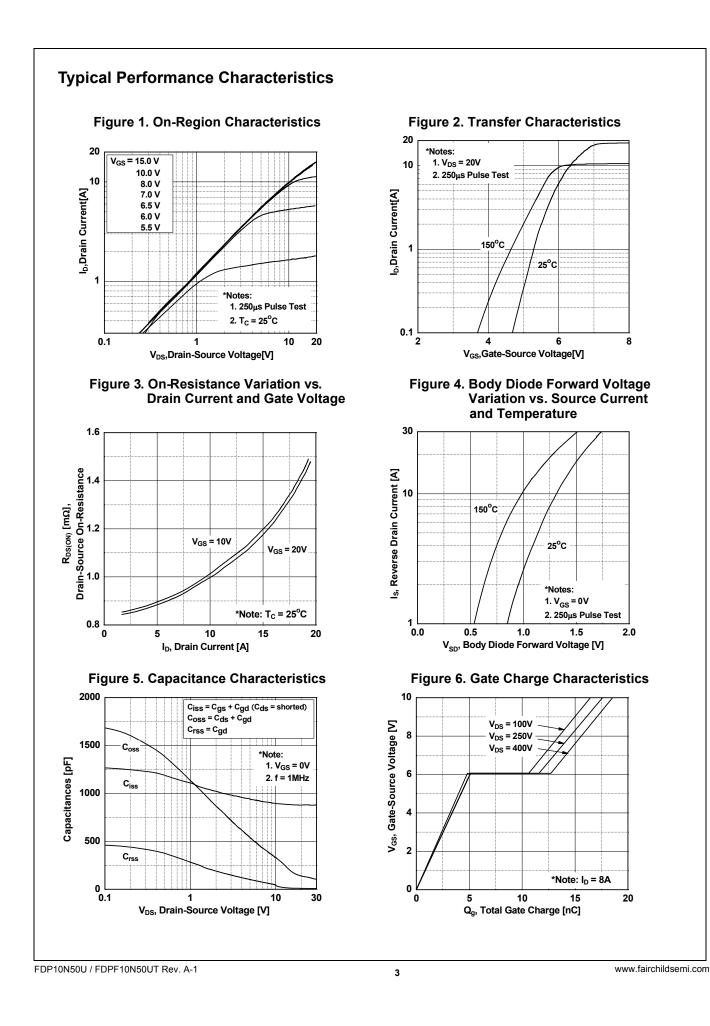
Symbol	Parameter			FDP10N50U	FDPF10N50UT	Units
V _{DSS}	Drain to Source Voltage			5	V	
V _{GSS}	Gate to Source Voltage			±30		V
ID	Drain Current	-Continuous (T _C = 25 ^o C)		8	8*	•
		-Continuous ($T_C = 100^{\circ}C$)		4.8	4.8*	A
I _{DM}	Drain Current	- Pulsed	(Note 1)	32	32*	А
E _{AS}	Single Pulsed Avalanche Energy (No		(Note 2)	320		mJ
I _{AR}	Avalanche Current		(Note 1)	8		А
E _{AR}	Repetitive Avalanche Energy		(Note 1)	12.5		mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	20		V/ns
P _D	Power Dissipation	(T _C = 25 ^o C)		125	42	W
		- Derate above 25°C		1.0	0.33	W/ºC
T _J , T _{STG}	Operating and Storage Temperature Range			-55 t	o +150	°C
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			3	300	°C

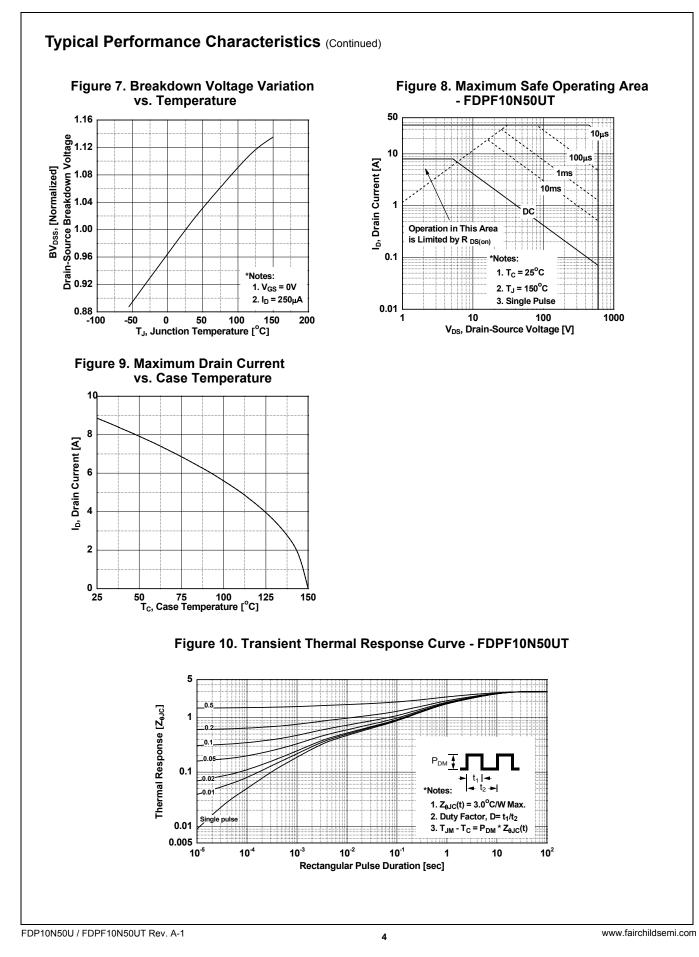
Thermal Characteristics

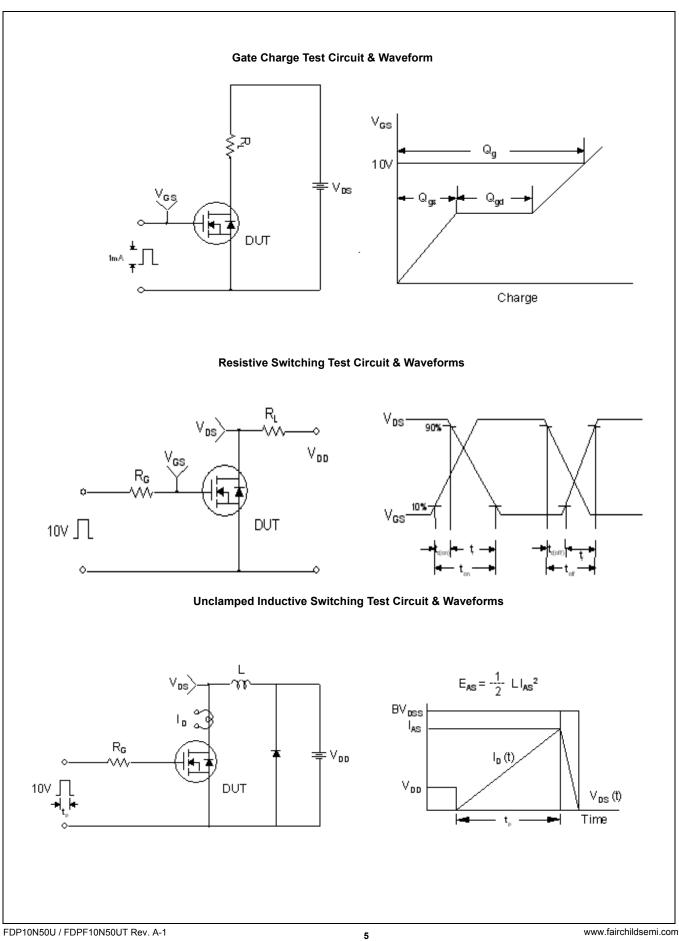
Symbol	Parameter	FDP10N50U	FDPF10N50UT	Units
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	1.0	3.0	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient	62.5	62.5	0/00

D
2
¥
5
150U
\
П
Ü
J
3
¥
5
ö
-
Ζ
l-Chan
4
ฉ
3
Z
Inel N
2
N
)SFE
Ξ.
H

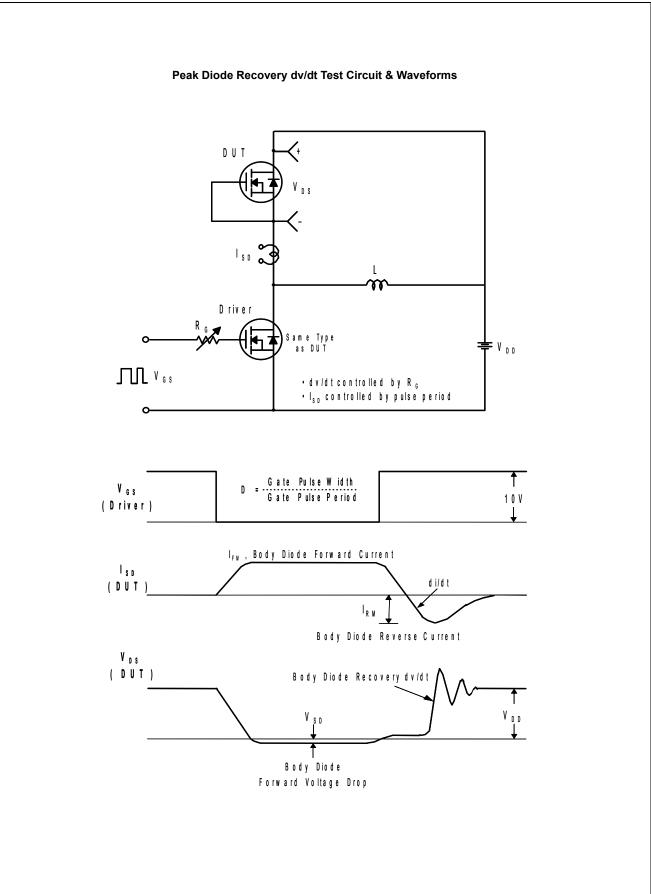
Device Marking Device		Packag	ge Reel Size Tap		e Width		Quantit	у
<u> </u>		TO-220) -		-		50	-
		TO-220	F -		-		50	
l Char	acteristics							
	Parameter		Test Condition	ıs	Min.	Тур.	Max.	Units
cteristic	S		I					
		$I_{\rm D} = 250 \mu A$ $V_{\rm CO} = 0V$ T = $25^{\circ}C$		500	-	_	V	
	U		$I_D = 250 \mu A$, Referenced to $25^{\circ}C$		000			-
V _{DSS} Breakdown Voltage Temperature Image: Transmission of the second se					-	0.6	-	V/ºC
Zara C			V _{DS} = 500V, V _{GS} = 0V		-	-	25	A
Zero Ga	ate voltage Drain Curre	ent	V _{DS} = 400V, T _C = 125 ^o C		-	-	250	μA
Gate to Body Leakage Current		t	V_{GS} = ±30V, V_{DS} = 0V		-	-	±100	nA
teristic	s							
			$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	3.0	-	5.0	V	
Static D)rain to Source On Res	istance			-	0.85	1.05	Ω
Forwar					-	8.5	-	S
						850	1130	pF
•	t Capacitance		V _{DS} = 25V, V _{GS} = 0V f = 1MHz		-			pF pF
					-			pF
	•	;						nC
	Gate to Source Gate Charge		V _{DS} = 400V, I _D = 10A V _{GS} = 10V (Note 4, 5)				24	nC
						-		
Gate to					-	7.5	-	nC
Charac	teristics						r	
	On Delay Time			_	-	15	40	ns
			V_{DD} = 250V, I_D = 10A R_G = 25 Ω , V_{GS} = 10V (Note 4, 5)		-	38	86	ns
	,				-	46	102	ns
Turn-Of	f Fall Time				-	33	76	ns
rce Dio	de Characteristic	S						
Maximu	m Continuous Drain to	Source Diode	e Forward Current		-	-	8	Α
					-	-		Α
Drain to	Source Diode Forwar	d Voltage	$V_{GS} = 0V, I_{SD} = 8A$		-	-	1.6	V
Reverse	e Recovery Time	0			-	44	-	ns
Reverse	e Recovery Charge		dl _F /dt = 100A/µs	(Note 4)	-	45	-	nC
	I Char cteristic Drain to Breakdd Coeffici Zero Ga Gate to Cteristic Gate Ti Static D Forward Characto Gate to Gate to Gate to Gate to Gate to Gate to Gate to Gate to Gate to Characc Turn-Or Turn-Or Turn-Of Turn-	Il Characteristics Parameter Cteristics Drain to Source Breakdown V Breakdown Voltage Temperate Coefficient Zero Gate Voltage Drain Curree Gate to Body Leakage Curren Cteristics Gate Threshold Voltage Static Drain to Source On Res Forward Transconductance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Total Gate to Drain "Miller" Charge Gate to Drain "Miller" Charge Characteristics Turn-On Delay Time Turn-Off Delay Time Turn-Off Fall Time Ce Diode Characteristic Maximum Continuous Drain to Maximum Pulsed Drain to Source	I Characteristics Parameter Cteristics Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Body Leakage Current Cteristics Gate Threshold Voltage Static Drain to Source On Resistance Forward Transconductance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Total Gate to Drain "Miller" Charge Gate to Drain "Miller" Charge Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time rce Diode Characteristics Maximum Continuous Drain to Source Diode Maximum Pulsed Drain to Source Diode Forward Voltage	I Characteristics Test Condition Iteristics ID Test Condition Streakdown Voltage Temperature Coefficient ID 250μ A, V _{GS} = 0V, T Breakdown Voltage Temperature Coefficient ID 250μ A, Referenced Zero Gate Voltage Drain Current V_{DS} = 500V, V_{GS} = 0V VDS $400V$, T_C = 125°C Gate to Body Leakage Current V_{GS} = $t^{30}V$, V_{DS} = 0V Static Drain to Source On Resistance V_{GS} = 10V, I_D = 4A Forward Transconductance V_{DS} = 20V, I_D = 4A Characteristics VDS = 20V, I_D = 4A Input Capacitance V_{DS} = 25V, V_{GS} = 0V Gate to Source Gate Charge V_{DS} = 400V, I_D = 10A Gate to Source Gate Charge V_{DS} = 400V, I_D = 10A Gate to Drain "Miller" Charge V_{DD} = 250V, I_D = 10A Turn-On Delay Time V_{CS} = 10V Turn-On Delay Time V_{GS} = 25 Ω , V_{GS} = 10V Turn-Off Delay Time V_{GS} = 25 Ω , V_{GS} = 10V Turn-Off Fall Time V_{GS} = 25 Ω , V_{GS} = 10V Turn-Off Fall Time V_{GS} = 0V, I_S = 8A Maximum Pulsed Drain to Source Diode Forward Current	I Characteristics Test Conditions Drain to Source Breakdown Voltage Ip = 250µA, V _{GS} = 0V, T _J = 25°C Breakdown Voltage Temperature Coefficient Ip = 250µA, Referenced to 25°C Breakdown Voltage Temperature Coefficient V _{DS} = 500V, V _{GS} = 0V Zero Gate Voltage Drain Current $V_{DS} = 500V, V_{GS} = 0V$ Zero Gate Voltage Drain Current $V_{GS} = 400V, T_C = 125°C$ Gate to Body Leakage Current $V_{GS} = 400V, T_C = 125°C$ Gate Threshold Voltage $V_{GS} = 10V, I_D = 40$ Static Drain to Source On Resistance $V_{GS} = 10V, I_D = 4A$ Forward Transconductance $V_{DS} = 20V, I_D = 4A$ (Note 4) Characteristics Input Capacitance $V_{DS} = 25V, V_{GS} = 0V$ (Note 4) Characteristics Input Capacitance $V_{DS} = 400V, I_D = 10A$ (Note 4, 5) Characteristics Turn-On Delay Time $V_{DD} = 250V, V_{GS} = 10V$ (Note 4, 5) Characteristics Turn-On Rise Time $V_{DD} = 250V, I_D = 10A$ (Note 4, 5) Chode Characteristics <th< td=""><td>I CharacteristicsParameterTest ConditionsMin.SteristicsID = 250µA, V_{GS} = 0V, T_J = 25°C500Breakdown Voltage Temperature CoefficientID = 250µA, Referenced to 25°C-Zero Gate Voltage Drain Current$V_{DS} = 500V, V_{GS} = 0V$-Gate to Body Leakage Current$V_{GS} = 400V, T_C = 125°C$-Gate to Body Leakage Current$V_{GS} = 400V, T_C = 125°C$-Gate Threshold Voltage$V_{GS} = 10V, I_D = 250µA$3.0Static Drain to Source On Resistance$V_{GS} = 10V, I_D = 4A$Forward Transconductance$V_{DS} = 20V, I_D = 4A$-CharacteristicsInput Capacitance$V_{DS} = 25V, V_{GS} = 0V$-Output Capacitance$V_{DS} = 25V, V_{GS} = 0V$-Total Gate Charge at 10V$V_{DS} = 400V, I_D = 10A$-Gate to Drain "Miller" Charge$V_{DS} = 400V, I_D = 10A$-Gate to Drain "Miller" Charge$V_{CS} = 10V$-Turn-On Delay Time$P_{CS} = 25\Omega, V_{GS} = 10V$-Turn-Off Delay Time$P_{CS} = 25\Omega, V_{GS} = 10V$-Turn-Off Delay Time$P_{CS} = 25\Omega, V_{GS} = 10V$-Turn-Off Fall Time$V_{CS} = 25\Omega, V_{GS} = 10V$-Turn-Off Fall Time$V_{CS} = 0V, I_{SD} = 8A$-Turn-Off Fall Time$V_{GS} = 0V, I_{SD} = 8A$-Turn-Off Dolay Time$P_{GS} = 0V, I_{SD} = 8A$-Turn-Off Fall Time$V_{CS} = 0V, I_{SD} = 8A$-</td><td>I CharacteristicsMin.Typ.SteristicsDrain to Source Breakdown Voltage$I_D = 250 \mu A$, $V_{GS} = 0V$, $T_J = 25^{\circ}C$500Breakdown Voltage Temperature$I_D = 250 \mu A$, Referenced to $25^{\circ}C$0.6Coefficient$V_{DS} = 500V, V_{GS} = 0V$-Zero Gate Voltage Drain Current$V_{DS} = 500V, V_{GS} = 0V$-Gate to Body Leakage Current$V_{GS} = 400V, T_C = 125^{\circ}C$-Gate to Body Leakage Current$V_{GS} = 400V, T_C = 125^{\circ}C$-Gate Threshold Voltage$V_{GS} = 430V, V_{DS} = 0V$-Static Drain to Source On Resistance$V_{GS} = 10V, I_D = 4A$-Output Capacitance$V_{DS} = 25V, V_{GS} = 0V$-BreacteristicsInput CapacitanceV_{DS} = 25V, V_{GS} = 0V-Breacteristics850Output CapacitanceV_{DS} = 25V, V_{GS} = 0V-Input CapacitanceV_{DS} = 210V-115Gate to Source Gate ChargeV_{DS} = 400V, I_D = 10A-18Gate to Drain "Miller" ChargeV_{DS} = 10V-138Turn-On Delay TimeV_{DD} = 250V, I_D = 10A-33Turn-Off Delay TimeV_{DS} = 250, V_{GS} = 10V-33Turn-Off Delay TimeV_{DS} = 250, V_{CS} = 10V-33Turn-Off Delay Time-15-33Turn-Off Delay Time33Turn-Off Delay TimeTurn-Off Sell TimeSource Diode Forward Current-<td>I Characteristics Min. Typ. Max. cteristics Drain to Source Breakdown Voltage $I_D = 250\mu A, V_{GS} = 0V, T_J = 25^{\circ}C$ 500 - - Breakdown Voltage Temperature Coefficient $I_D = 250\mu A, Referenced to 25^{\circ}C$ - 0.6 - Zero Gate Voltage Drain Current $V_{DS} = 500V, V_{GS} = 0V$ - - 250 Gate to Body Leakage Current $V_{GS} = \pm 30V, V_{DS} = 0V$ - - 250 Gate Threshold Voltage $V_{GS} = \pm 30V, V_{DS} = 0V$ - - ±100 transconductance $V_{GS} = \pm 30V, V_{DS} = 0V$ - - ±100 Static Drain to Source On Resistance $V_{GS} = 10V, I_D = 4A$ - 0.85 1.05 Forward Transconductance $V_{DS} = 20V, I_D = 4A$ - 0.85 1.55 Input Capacitance $V_{DS} = 25V, V_{GS} = 0V$ - 18 24 Gate to Charge at 10V $V_{DS} = 400V, I_D = 10A$ - 18 24 Gate to Drain "Miller" Charge $V_{DS} = 10V, I_D = 10A$ - 18 24</td></td></th<>	I CharacteristicsParameterTest ConditionsMin.SteristicsID = 250µA, V_{GS} = 0V, T_J = 25°C500Breakdown Voltage Temperature CoefficientID = 250µA, Referenced to 25°C-Zero Gate Voltage Drain Current $V_{DS} = 500V, V_{GS} = 0V$ -Gate to Body Leakage Current $V_{GS} = 400V, T_C = 125°C$ -Gate to Body Leakage Current $V_{GS} = 400V, T_C = 125°C$ -Gate Threshold Voltage $V_{GS} = 10V, I_D = 250µA$ 3.0Static Drain to Source On Resistance $V_{GS} = 10V, I_D = 4A$ Forward Transconductance $V_{DS} = 20V, I_D = 4A$ -CharacteristicsInput Capacitance $V_{DS} = 25V, V_{GS} = 0V$ -Output Capacitance $V_{DS} = 25V, V_{GS} = 0V$ -Total Gate Charge at 10V $V_{DS} = 400V, I_D = 10A$ -Gate to Drain "Miller" Charge $V_{DS} = 400V, I_D = 10A$ -Gate to Drain "Miller" Charge $V_{CS} = 10V$ -Turn-On Delay Time $P_{CS} = 25\Omega, V_{GS} = 10V$ -Turn-Off Delay Time $P_{CS} = 25\Omega, V_{GS} = 10V$ -Turn-Off Delay Time $P_{CS} = 25\Omega, V_{GS} = 10V$ -Turn-Off Fall Time $V_{CS} = 25\Omega, V_{GS} = 10V$ -Turn-Off Fall Time $V_{CS} = 0V, I_{SD} = 8A$ -Turn-Off Fall Time $V_{GS} = 0V, I_{SD} = 8A$ -Turn-Off Dolay Time $P_{GS} = 0V, I_{SD} = 8A$ -Turn-Off Fall Time $V_{CS} = 0V, I_{SD} = 8A$ -	I CharacteristicsMin.Typ.SteristicsDrain to Source Breakdown Voltage $I_D = 250 \mu A$, $V_{GS} = 0V$, $T_J = 25^{\circ}C$ 500Breakdown Voltage Temperature $I_D = 250 \mu A$, Referenced to $25^{\circ}C$ 0.6Coefficient $V_{DS} = 500V, V_{GS} = 0V$ -Zero Gate Voltage Drain Current $V_{DS} = 500V, V_{GS} = 0V$ -Gate to Body Leakage Current $V_{GS} = 400V, T_C = 125^{\circ}C$ -Gate to Body Leakage Current $V_{GS} = 400V, T_C = 125^{\circ}C$ -Gate Threshold Voltage $V_{GS} = 430V, V_{DS} = 0V$ -Static Drain to Source On Resistance $V_{GS} = 10V, I_D = 4A$ -Output Capacitance $V_{DS} = 25V, V_{GS} = 0V$ -BreacteristicsInput CapacitanceV_{DS} = 25V, V_{GS} = 0V-Breacteristics850Output CapacitanceV_{DS} = 25V, V_{GS} = 0V-Input CapacitanceV_{DS} = 210V-115Gate to Source Gate ChargeV_{DS} = 400V, I_D = 10A-18Gate to Drain "Miller" ChargeV_{DS} = 10V-138Turn-On Delay TimeV_{DD} = 250V, I_D = 10A-33Turn-Off Delay TimeV_{DS} = 250, V_{GS} = 10V-33Turn-Off Delay TimeV_{DS} = 250, V_{CS} = 10V-33Turn-Off Delay Time-15-33Turn-Off Delay Time33Turn-Off Delay TimeTurn-Off Sell TimeSource Diode Forward Current- <td>I Characteristics Min. Typ. Max. cteristics Drain to Source Breakdown Voltage $I_D = 250\mu A, V_{GS} = 0V, T_J = 25^{\circ}C$ 500 - - Breakdown Voltage Temperature Coefficient $I_D = 250\mu A, Referenced to 25^{\circ}C$ - 0.6 - Zero Gate Voltage Drain Current $V_{DS} = 500V, V_{GS} = 0V$ - - 250 Gate to Body Leakage Current $V_{GS} = \pm 30V, V_{DS} = 0V$ - - 250 Gate Threshold Voltage $V_{GS} = \pm 30V, V_{DS} = 0V$ - - ±100 transconductance $V_{GS} = \pm 30V, V_{DS} = 0V$ - - ±100 Static Drain to Source On Resistance $V_{GS} = 10V, I_D = 4A$ - 0.85 1.05 Forward Transconductance $V_{DS} = 20V, I_D = 4A$ - 0.85 1.55 Input Capacitance $V_{DS} = 25V, V_{GS} = 0V$ - 18 24 Gate to Charge at 10V $V_{DS} = 400V, I_D = 10A$ - 18 24 Gate to Drain "Miller" Charge $V_{DS} = 10V, I_D = 10A$ - 18 24</td>	I Characteristics Min. Typ. Max. cteristics Drain to Source Breakdown Voltage $I_D = 250\mu A, V_{GS} = 0V, T_J = 25^{\circ}C$ 500 - - Breakdown Voltage Temperature Coefficient $I_D = 250\mu A, Referenced to 25^{\circ}C$ - 0.6 - Zero Gate Voltage Drain Current $V_{DS} = 500V, V_{GS} = 0V$ - - 250 Gate to Body Leakage Current $V_{GS} = \pm 30V, V_{DS} = 0V$ - - 250 Gate Threshold Voltage $V_{GS} = \pm 30V, V_{DS} = 0V$ - - ±100 transconductance $V_{GS} = \pm 30V, V_{DS} = 0V$ - - ±100 Static Drain to Source On Resistance $V_{GS} = 10V, I_D = 4A$ - 0.85 1.05 Forward Transconductance $V_{DS} = 20V, I_D = 4A$ - 0.85 1.55 Input Capacitance $V_{DS} = 25V, V_{GS} = 0V$ - 18 24 Gate to Charge at 10V $V_{DS} = 400V, I_D = 10A$ - 18 24 Gate to Drain "Miller" Charge $V_{DS} = 10V, I_D = 10A$ - 18 24



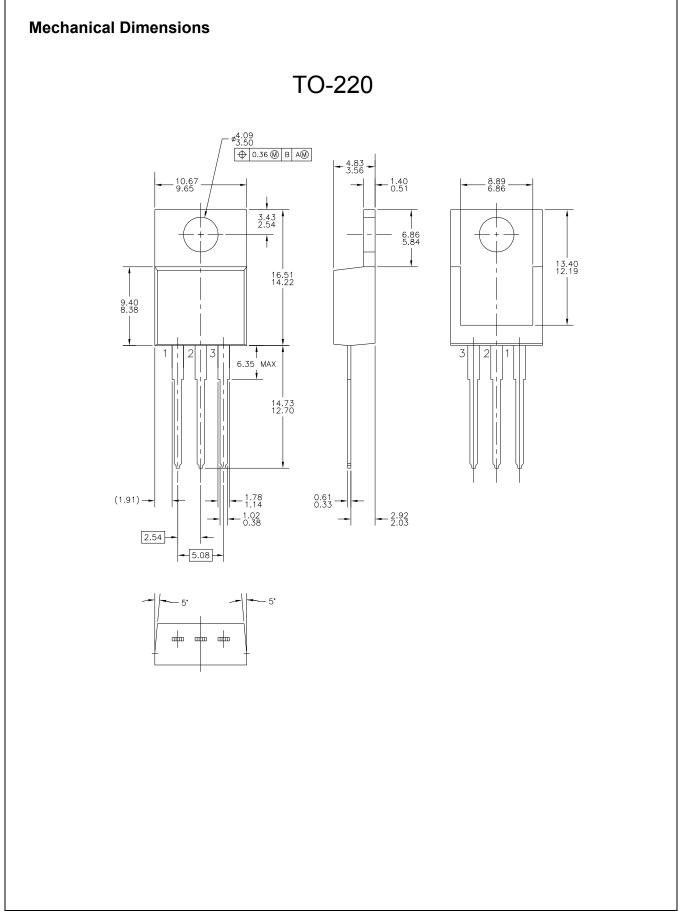




FDP10N50U / FDPF10N50UT N-Channel MOSFET



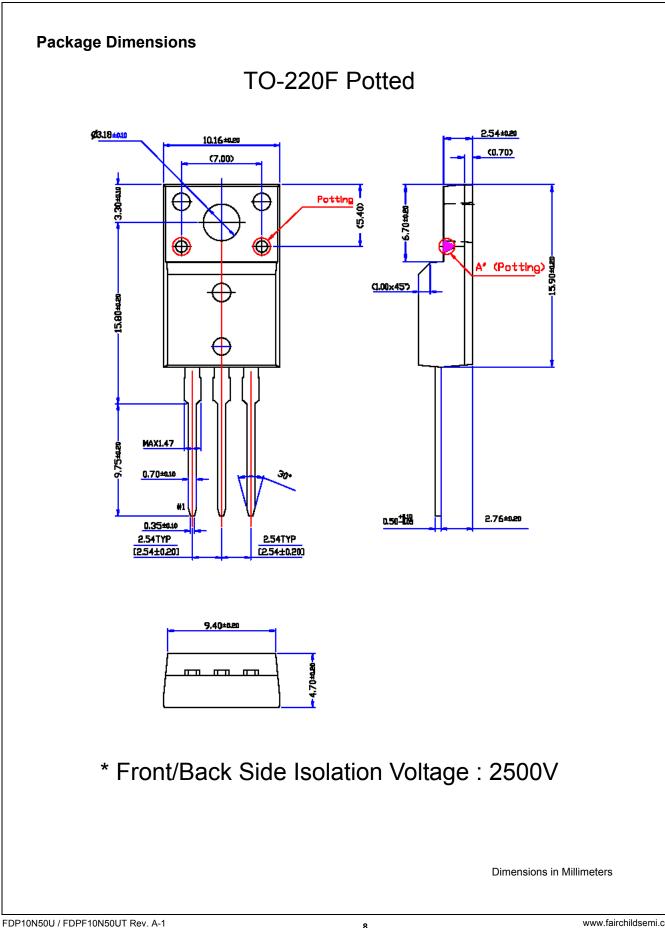
www.fairchildsemi.com



FDP10N50U / FDPF10N50UT N-Channel MOSFET

7

www.fairchildsemi.com





SEMICONDUCTOR

TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

AccuPower™	FPS™	PowerTrench [®]	The Power Franchise
Auto-SPM™	F-PFS™	PowerXS™	the
Build it Now™	FRFET [®]	Programmable Active Droop™	p uwer ®
CorePLUS™	Global Power Resource SM	QFET®	II di Ullise
CorePOWER™	Green FPS™	QS™	TITYBOOSL
CROSSVOLT™	Green FPS™ e-Series™	Quiet Series™	TinyBuck™
CTL™	G <i>max</i> ™	RapidConfigure™	TinyCalc™
Current Transfer Logic™	GTO™		TinyLogic [®]
EcoSPARK [®]	IntelliMAX™	т	TINYOPTO™
EfficentMax™	ISOPLANAR™	Saving our world, 1mW /W /kW at a time™	TinyPower™
EZSWITCH™*	MegaBuck™	SmartMax™	TinyPWM™
—— •	MIČROCOUPLER™	SMART START™	TinyWire™
	MicroFET™	SPM®	TriFault Detect™
— ®	MicroPak™	STEALTH™	TRUECURRENT™*
F	MillerDrive™	SuperFET™	\mathcal{U}
airchild®	MotionMax™	SuperSOT™-3	SerDes
airchild Semiconductor®	Motion-SPM™	SuperSOT™-6	UHC®
ACT Quiet Series™	OPTOLOGIC®	SuperSOT™-8	Ultra FRFET™
ACT®	OPTOPLANAR [®]	SupreMOS™	UniFET™
AST®	®	SyncFET™	VCX™
astvCore™		Sync-Lock™	VisualMax™
ETBench™	PDP SPM™	SYSTEM ®*	XS™
FlashWriter [®] *	PDP SPM™ Power-SPM™	GENERAL	

DISCLAIMER FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, O R DESI GN. FAIRCHILD DOES N OT ASSUME ANY LIABILITY AR ISING OUT OF THE APPL ICATION OR U SE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein:

- Life support devices or systems are devices or systems which, (a) are 1. intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use pr ovided in t he labe ling, can be reasonably expected to result in a significant injury of the user.
- A critical component in an y component of a life support, device, or 2. system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness

ANTI-COUNTERFEITING POLICY

Fairchild Semicon ductor Corpor ation's Ant i-Counterfeiting Poli cy. Fairchild's An ti-Counterfeiting Policy is also st ated on our external websit e, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are li sted by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's guality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.
	•	Rev.